## P-Channel Enhancement Mode Power MOSFET

## Description

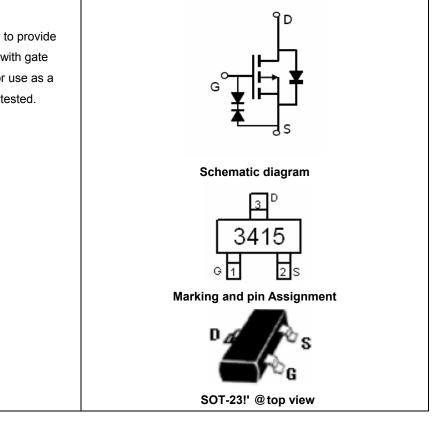
The HM3415E uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications .It is ESD protested.

#### **General Features**

- $V_{DS} = -20V, I_D = -4A$   $R_{DS(ON)} < 53m\Omega @ V_{GS} = -2.5V$   $R_{DS(ON)} < 40m\Omega @ V_{GS} = -4.5V$ ESD Rating: 2500V HBM
- High Power and current handing capability
- Lead free product is acquired
- Surface mount package

## Application

- PWM application
- Load switch



### Package Marking And Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
3415	HM3415E	SOT-23-3L	Ø180mm	8 mm	3000 units

#### Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	-20	V
Gate-Source Voltage	Vgs	±10	V
Drain Current-Continuous	Ι <sub>D</sub>	-4	А
Drain Current-Pulsed (Note 1)	I <sub>DM</sub>	-30	А
Maximum Power Dissipation	PD	1.4	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 150	°C

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Ambient (Note 2) R <sub>0JA</sub>	89.3	°C/W
---	------	------

#### Electrical Characteristics (TA=25<sup>°</sup>C unless otherwise noted)

Parameter	Symbol	nbol Condition		Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =-250µA	-20		-	V

Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =-20V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±10V,V <sub>DS</sub> =0V	-	-	±10	μA
On Characteristics (Note 3)						L
Gate Threshold Voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> ,I <sub>D</sub> =-250µA	-0.4	-0.65	-1.0	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4A	-	31	40	mΩ
Drain-Source On-State Resistance		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-4A	-	40	53	mΩ
Forward Transconductance	<b>g</b> fs	V <sub>DS</sub> =-5V,I <sub>D</sub> =-4A	8	-	-	S
Dynamic Characteristics (Note4)				•		
Input Capacitance	Clss		-	950	-	PF
Output Capacitance	Coss	V <sub>DS</sub> =-10V,V <sub>GS</sub> =0V, F=1.0MHz	-	165	-	PF
Reverse Transfer Capacitance	C <sub>rss</sub>		-	120	-	PF
Switching Characteristics (Note 4)		·				
Turn-on Delay Time	t <sub>d(on)</sub>		-	12		nS
Turn-on Rise Time	tr	V <sub>DD</sub> =-10V,R <sub>L</sub> =2. 5Ω	-	10		nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =-4.5V, $R_{GEN}$ =3 $\Omega$	-	19		nS
Turn-Off Fall Time	t <sub>f</sub>		-	25		nS
Total Gate Charge	Qg	(-40)(1-40)	-	12		nC
Gate-Source Charge	Q <sub>gs</sub>	V <sub>DS</sub> =-10V,I <sub>D</sub> =-4A, V <sub>GS</sub> =-4.5V	-	1.4	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	VGS4.3V	-	3.6	-	nC
Drain-Source Diode Characteristics			·			-
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =-1A	-	-	-1.2	V
Diode Forward Current (Note 2)	Is		-	-	-2.2	А

#### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

**2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.

**3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.

4. Guaranteed by design, not subject to production

## **TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

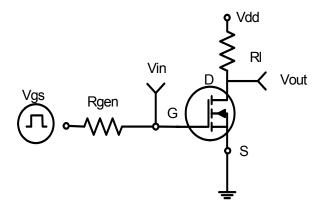
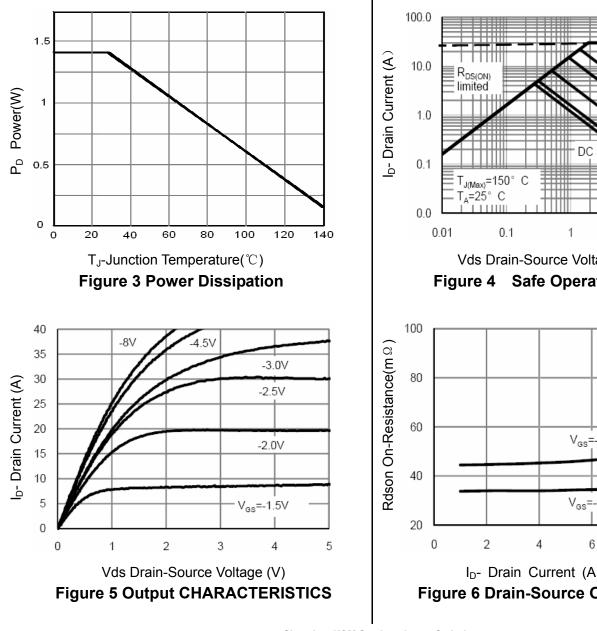


Figure 1:Switching Test Circuit



t<sub>on</sub> t t. t<sub>d(on)</sub> t<sub>d(off)</sub> 90% 90% Vout **INVERTED** 10% 10% 90% V<sub>IN</sub> 50% 50% 10% **PULSE WIDTH** 

Figure 2:Switching Waveforms

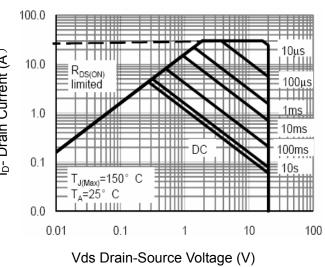
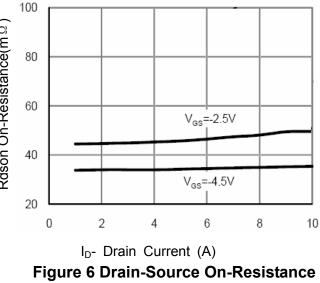
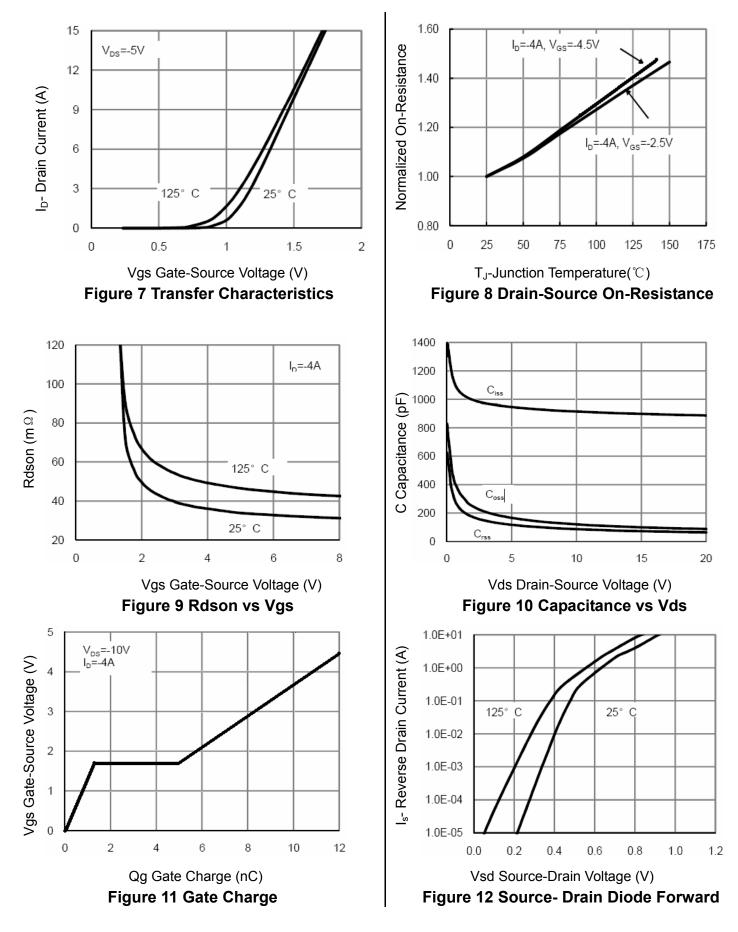
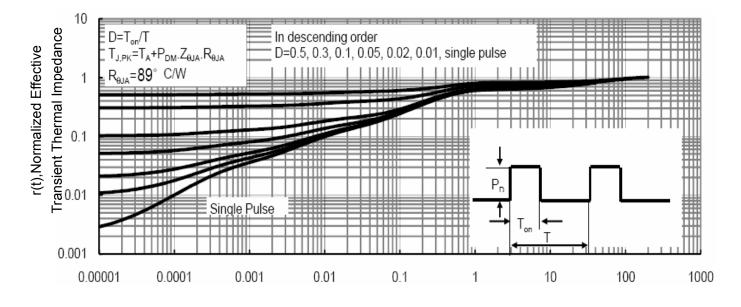


Figure 4 Safe Operation Area

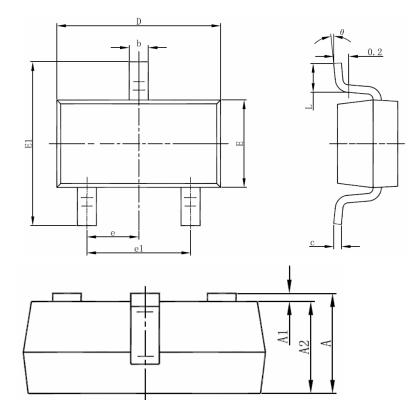






Square Wave Pluse Duration(sec) Figure 13 Normalized Maximum Transient Thermal Impedance

# **SOT-23-3L PACKAGE INFORMATION**



Symbol	Dimensions Ir	n Millimeters	Dimensions In Inches		
Symbol	Min	Max	Min	Max	
A	1.050	1.250	0.041	0.049	
A1	0.000	0.100	0.000	0.004	
A2	1.050	1.150	0.041	0.045	
b	0.300	0.500	0.012	0.020	
С	0.100	0.200	0.004	0.008	
D	2.820	3.020	0.111	0.119	
E	1.500	1.700	0.059	0.067	
E1	2.650	2.950	0.104	0.116	
е	0.950	(BSC)	0.037(BSC)		
e1	1.800	2.000	0.071	0.079	
L	0.300	0.600	0.012	0.024	
θ	0°	8°	٥°	8°	

## NOTES

1. All dimensions are in millimeters.

2. Tolerance ±0.10mm (4 mil) unless otherwise specified

3. Package body sizes exclude mold flash and gate burrs. Mold flash at the non-lead sides should be less than 5 mils.

4. Dimension L is measured in gauge plane.

5. Controlling dimension is millimeter, converted inch dimensions are not necessarily exact.

## ATTENTION:

- Any and all H&M SEMI products described or contained herein do not have specifications that can handle applications that require extremely high levels of reliability, such as life-support systems, aircraft's control systems, or other applications whose failure can be reasonably expected to result in serious physical and/or material damage. Consult with your H&M SEMI representative nearest you before using any H&M SEMI products described or contained herein in such applications.
- H&M SEMI assumes no responsibility for equipment failures that result from using products at values that exceed, even momentarily, rated values (such as maximum ratings, operating condition ranges, or other parameters) listed in products specifications of any and all H&M SEMI products described or contained herein.
- Specifications of any and all H&M SEMI products described or contained herein stipulate the performance, characteristics, and functions of the described products in the independent state, and are not guarantees of the performance, characteristics, and functions of the described products as mounted in the customer's products or equipment. To verify symptoms and states that cannot be evaluated in an independent device, the customer should always evaluate and test devices mounted in the customer's products or equipment.
- H&M Semiconductor CO.,LTD. strives to supply high-quality high-reliability products. However, any and all semiconductor products fail with some probability. It is possible that these probabilistic failures could give rise to accidents or events that could endanger human lives, that could give rise to smoke or fire, or that could cause damage to other property. When designing equipment, adopt safety measures so that these kinds of accidents or events cannot occur. Such measures include but are not limited to protective circuits and error prevention circuits for safe design, redundant design, and structural design.
- In the event that any or all H&M SEMI products(including technical data, services) described or contained herein are controlled under any of applicable local export control laws and regulations, such products must not be exported without obtaining the export license from the authorities concerned in accordance with the above law.
- No part of this publication may be reproduced or transmitted in any form or by any means, electronic or mechanical, including photocopying and recording, or any information storage or retrieval system, or otherwise, without the prior written permission of H&M Semiconductor CO.,LTD.
- Information (including circuit diagrams and circuit parameters) herein is for example only; it is not guaranteed for volume production. H&M SEMI believes information herein is accurate and reliable, but no guarantees are made or implied regarding its use or any infringements of intellectual property rights or other rights of third parties.
- Any and all information described or contained herein are subject to change without notice due to product/technology improvement, etc. When designing equipment, refer to the "Delivery Specification" for the H&M SEMI product that you intend to use.
- This catalog provides information as of Sep.2010. Specifications and information herein are subject to change without notice.